

1. Record Nr.	UNINA9910455963803321
Titolo	Four-dimensional model assimilation of data [[electronic resource]] : a strategy for the earth system sciences // Panel on Model-Assimilated Data Sets for Atmospheric and Oceanic Research, Board on Atmospheric Sciences and Climate, Commission on Geosciences, Environment, and Resources, National Research Council
Pubbl/distr/stampa	Washington, D.C., : National Academy Press, 1991
ISBN	1-280-21168-7 9786610211685 0-309-58348-9 0-585-15546-1
Descrizione fisica	1 online resource (88 p.)
Soggetti	Atmospheric models Numerical weather forecasting - United States Atmospheric circulation - Computer simulation Ocean circulation - Computer simulation Electronic books.
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Bibliographic Level Mode of Issuance: Monograph
Nota di bibliografia	Includes bibliographical references (p. 70-75).

2. Record Nr.	UNISA996204464603316
Titolo	1996 IEEE International Conference on Microelectronic Test Structures
Pubbl/distr/stampa	[Place of publication not identified], : IEEE, 1996
Descrizione fisica	1 online resource (338 pages)
Disciplina	621.3815
Soggetti	Integrated circuits Microelectronics
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Bibliographic Level Mode of Issuance: Monograph
Sommario/riassunto	The papers included in this leading international conference examine test structures for microelectronic devices, their recent progress and future directions. Included is a detailed treatment of current developments in silicon and gallium arsenide microelectronic test structure research, implementation, and applications. Also addressed are advances in device characterization, such as increased miniaturization, reduced operating voltages and reduced power requirements through improved measurement and test techniques. Topics highlighted include: Process Characterization, Dimensional Measurements, Interconnection, SOI & Material Characterization, Reliability, Device Characterization, Capacitance Measurements, Statistics.